

NVRAM

15,358kr 10k

JW

GENERAL INSTRUMENT	ER59256
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Preliminary Information
August 1983

256 Bit Serial Electrically Erasable and Programmable ROM

Features

- Low cost
- 16x16 serial EEPROM
- Single Supply Operation (5V±10%)
- TTL Compatible
- N-Channel SNOS technology
- Binary addressing
- Word and chip erasable
- 10 years' data retention after 10⁴ erase/write cycles per word
- Unlimited read accesses

Description

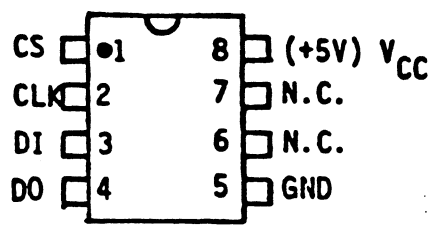
The ER59256 is a low cost, serial EEPROM manufactured in General Instrument's proven SNOS technology. The key features of this device are its +5V only operation and microcomputer compatible architecture. The input (DI) and output (DO) pins may be used separately or may be tied together to form a single I/O pin. Six 9 bit instructions can be executed. See Table 1. The instruction format has a logical "1" as a start bit, four bits as an op code, and four bits of address. See Table 1. Nonvolatile memory storage is guaranteed for 10 years over the temperature range of 0° to 70°C even after each word of memory has been rewritten up to 10,000 times.

Pin Functions

- CS Chip Select
- CLK Clock Input
- DI Serial Data Input
- DO Serial Data Output
- V_{CC} +5V Power Supply
- GND Ground

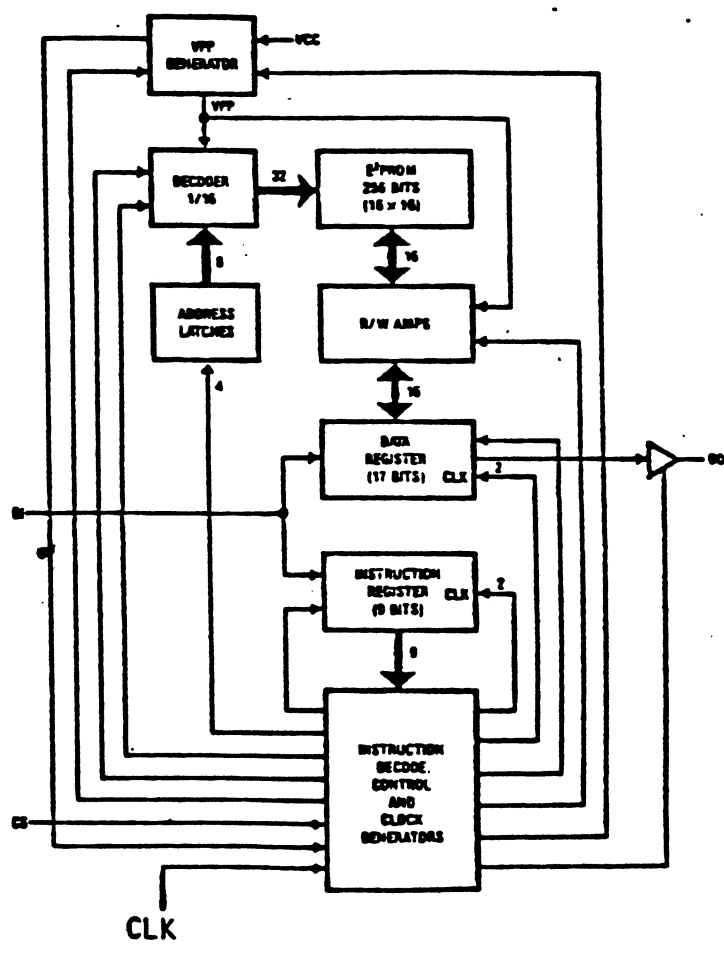
Pin Configuration

8 Pin Dual-in-Line



N.C. = No Internal Connection

Block Diagram



Ullsundavägen 174, 181 85 Bromma Lotsgatan 7, 414 58 Göteborg Regementsgatan 35, 217 53 Malmö Rudestelletta nr 81, Postboks 121, 1351 Rud, Norge	Tel 08/733 90 20 Tel 031/42 02 50 Tel 040/10 40 50 Tel (02) 13 61 70
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GYLLING Gylling Teledata AB

Instrument Corporation, 198

ELECTRICAL CHARACTERISTICS

Maximum Ratings *
 All inputs and outputs with respect to ground.....+6V-0.3V
 Storage temperature (unpowered and without data retention)...-65°C to 150°C. Soldering temperature of leads (10 seconds).....+300°C.

*Exceeding these ratings could cause permanent damage. Functional operation of this device at these conditions, or any other conditions outside those indicated in the operational sections of this specification, is not implied.

STANDARD CONDITIONS

(unless otherwise noted)

V_{CC} = +5 ± 10% volts

V_{EE} = 0 volts

Operating Temperature Range (T_A):
 0°C to 70°C

Data labelled "typical" is presented for design guidance only and is not guaranteed

General Instrument makes no warranty, expressed or implied, as to the merchantability or fitness for a particular purpose of this device or its software supplied to the customer.

DC CHARACTERISTICS

Characteristic	Sym.	Min.	Typ.	Max.	Units	Conditions
High Level Input Voltage	V _{IH}	2.0	-	V _{CC} +0.3	V	
Low Level Input Voltage	V _{IL}	-0.3	-	+0.8	V	
High Level Output Voltage	V _{OH}	2.4	-	V _{CC}	V	I _{OH} = -200µA
Low Level Output Voltage	V _{OL}	-	-	0.4	V	I _{OL} = 1.6mA
Input Leakage Current	I _{IL}	-	-	+10	µA	V _{IN} = GND to V _{CC}
Output Leakage Current	I _{OL}	-	-	+10	µA	V _{OUT} = GND to V _{CC}
POWER SUPPLY REQUIREMENTS						
Operating Current	I _{CC2}	-	-	10	mA	V _{CC} = 5.5V CS = 1
Standby Current	I _{CC3}	-	-	3	mA	V _{CC} = 5.5V CS = 0
E/W Operating Current	I _{CC3}	-	-	12	mA	V _{CC} = 5.5V

DC CHARACTERISTICS (continued)

Characteristic	Sym.	Min.	Typ.	Max.	Units	Conditions
Power Consumption (Operating)	Pcc1	-	-	55	mW	Vcc=5.5V CS=1
Power Consumption (Standby)	Pcc2	-	-	17	mW	Vcc=5.5V CS=0
Power Consumption (E/W)	Pcc3	-	-	66	mW	Vcc=5.5V CS=1

AC CHARACTERISTICS

Characteristic	Sym.	Min.	Typ.	Max.	Units	Conditions
Clock Frequency	f _{CLK}	4	-	250	KHZ	
Clock Duty Cycle	D _{CLK}	25	-	75	%	
Chip Select Setup Time	t _{CSS}	0.2	-	-	μs	
Chip Select Hold Time	t _{CSH}	0	-	-	μs	
Data Input Setup Time	t _{DIS}	0.4	-	-	μs	
Data Input Hold Time	t _{DIH}	0.4	-	-	μs	
DO Output Delay (H to L)	t _{PD1}	-	-	2	μs	C _L =100pf
DO Output Delay (L to H)	t _{PD2}	-	-	2	μs	C _L =100pf
Erase/Write Pulse Width	t _{E/W}	20	-	30	ms	
Input Capacitance	C _I	-	-	6	pf	V _{IN} =0V
Output Capacitance	C _O	-	-	10	pf	V _{OUT} =0V

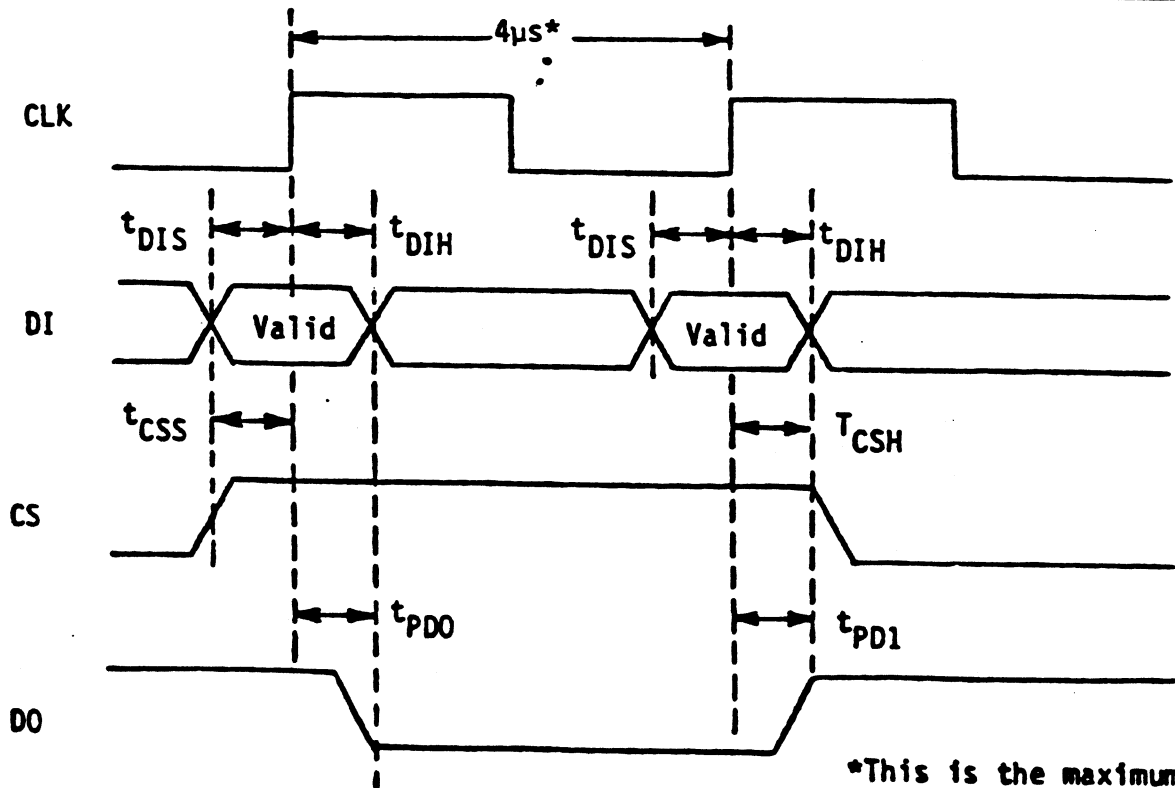
0-15 Address

See Figure 2

Instruction	SB	Op Code	Address	Data	Comments
READ	1	0100 1000	A3A2A1A0		Read register A3A2A1A0
WRITE	1	0100	A3A2A1A0	D15-D0	Write register A3A2A1A0
ERASE	1	1100	A3A2A1A0		Erase register A3A2A1A0
EWEN	1	0011	0000		Erase/write enable
EWDS	1	0000	0000		Erase/write disable
ERAL	1	0010	0000		Erase all registers

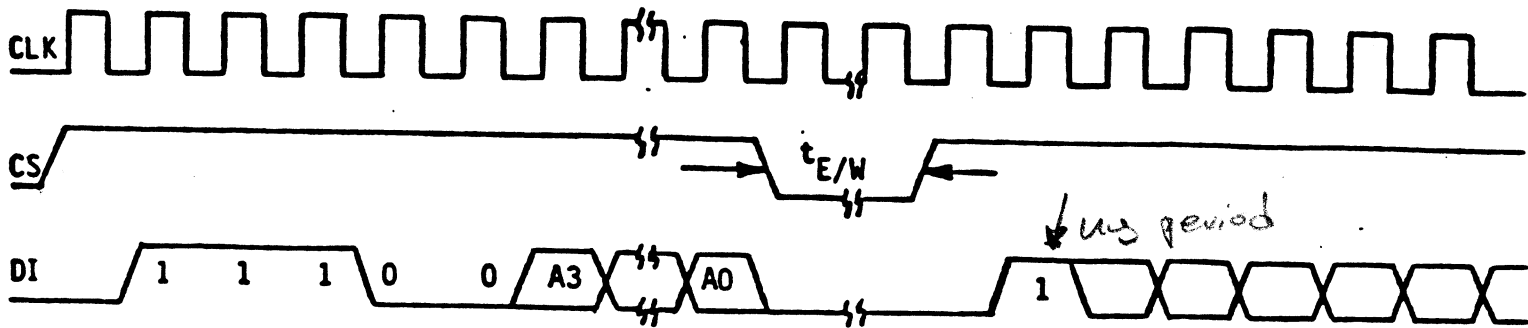
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16 bits register

Table 1 Instruction Set



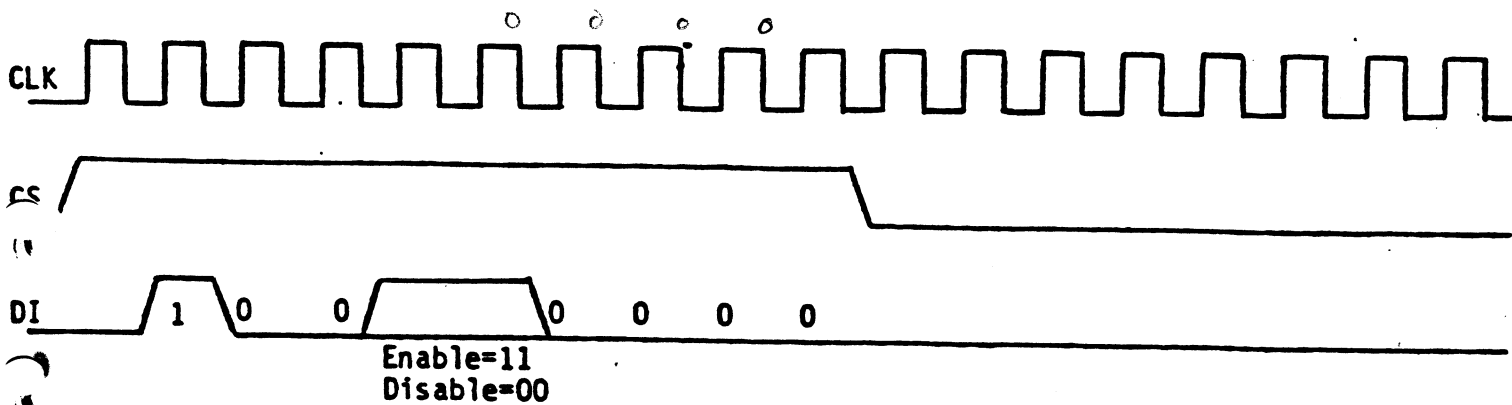
*This is the maximum clock frequency.

Figure 1. Synchronous Data Timing



Like most E²PROMS, the register must first be erased (all bits set to 1s) before the register can be written (certain bits set to 0s). After an ERASE instruction is input, CS is dropped low. This falling edge of CS determines the start of programming. The register at the address specified in the instruction is then set entirely to 1s. When the erase/write programming time ($t_{E/W}$) constraint has been satisfied, CS is brought up for at least one SK period. A new instruction may then be input. A low-power standby state may be achieved by dropping CS low.

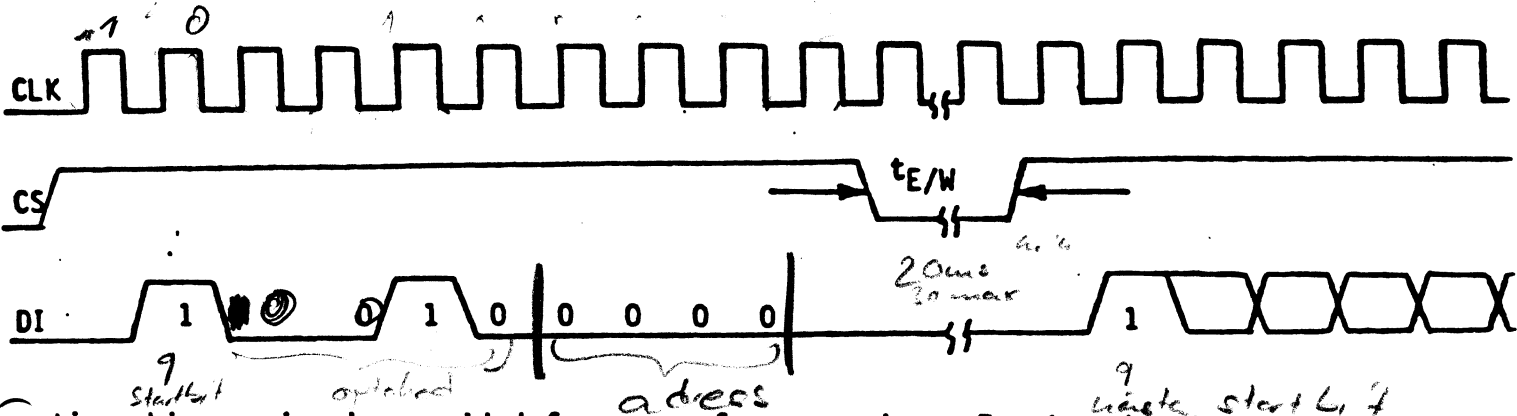
Figure 4. Erase Mode



Programming must be preceded once by a programming enable (EWEN) instruction. Programming remains enabled until a programming disable (EWDS) instruction is executed. The programming disable instruction is provided to protect against accidental data disturb. Execution of a READ instruction is independent of both EWEN and EWDS instructions.

Figure 5. Erase/Write Enable and Disable

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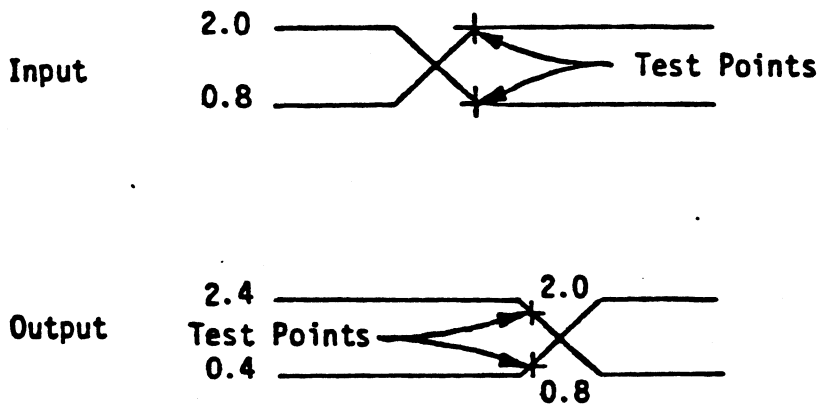


Chip erasing is provided for ease of programming. Erasing the chip means that all registers in the memory array have each bit set to a 1. Each register is then ready for a WRITE instruction.

1.5µs/level

Figure 6. Chip Erase Mode

A.C. Testing, Input and Output Waveforms



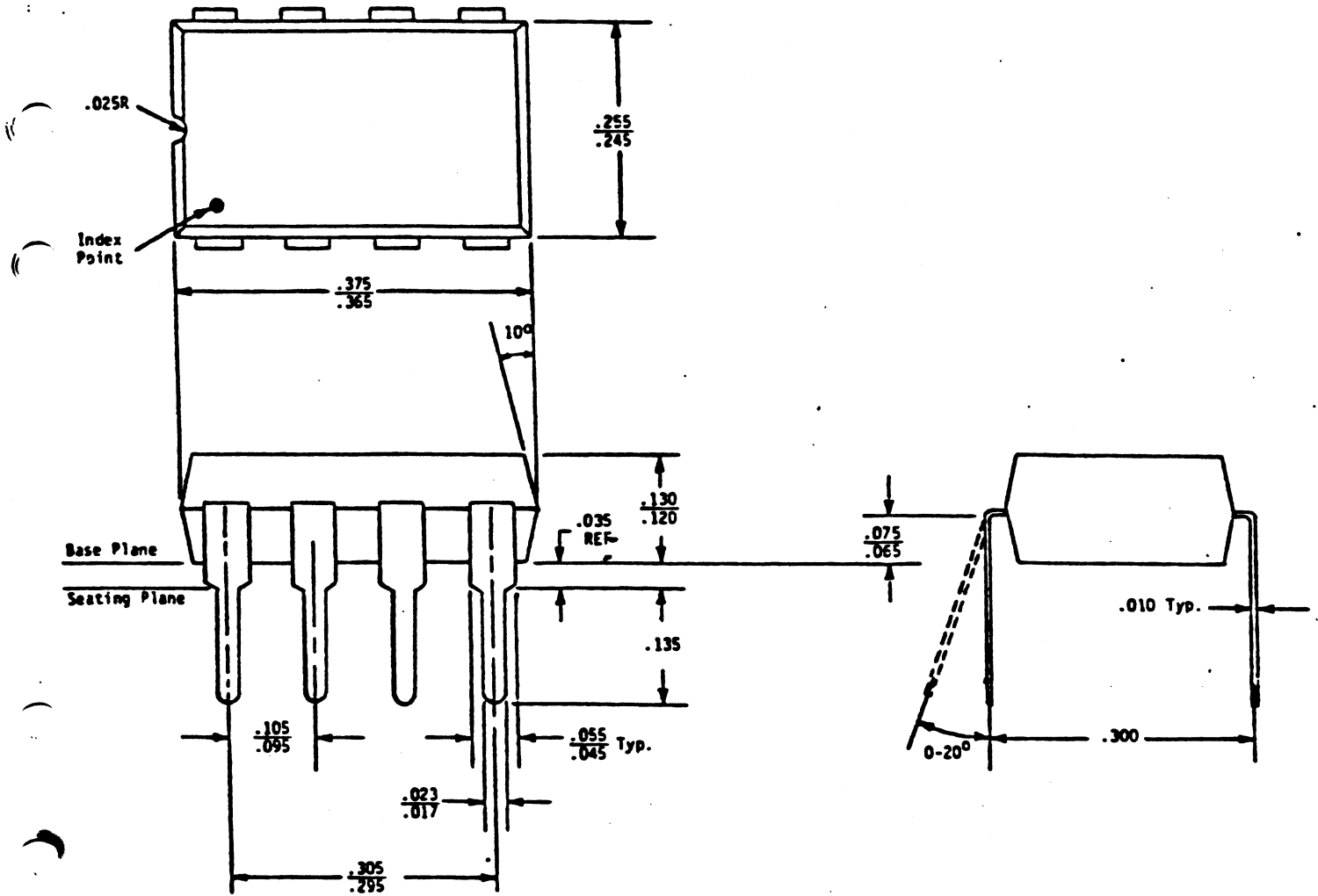
A.C. Testing: Inputs are driven at 2.0V for an input logic high and 0.8V for an input logic low. Timing measurements of the output waveforms are made at 2.0V for an output logic high and 0.8V for an output logic low.

GENERAL
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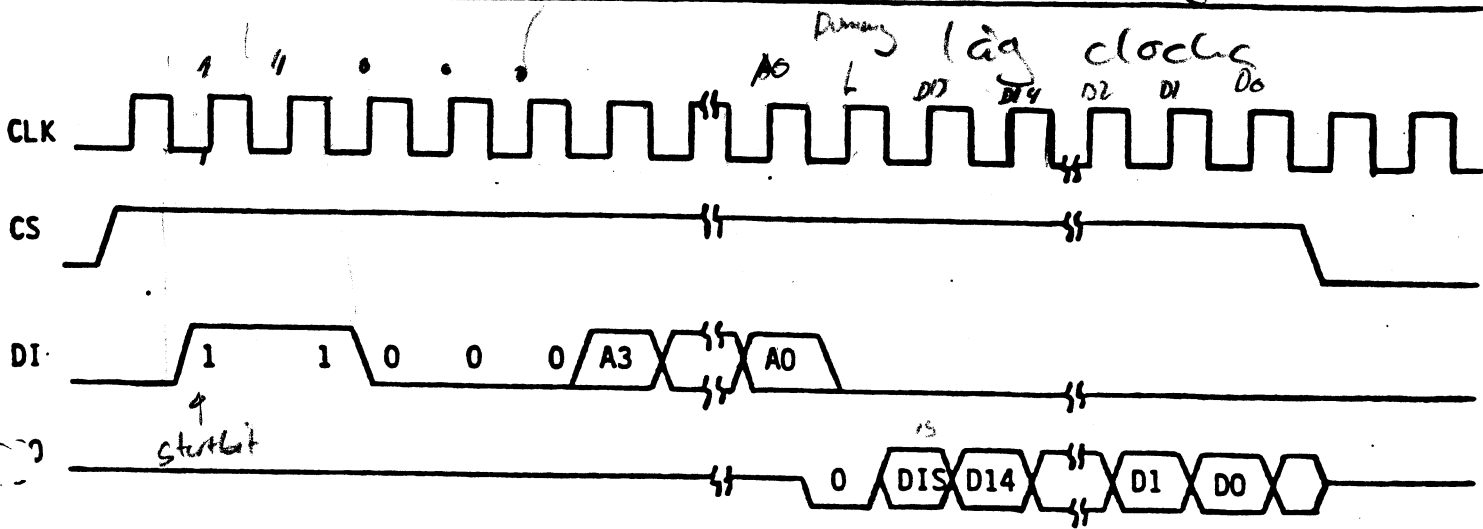
ER59256

PACKAGE OUTLINE

8 Lead Dual-in-Line (All dimensions are in inches)

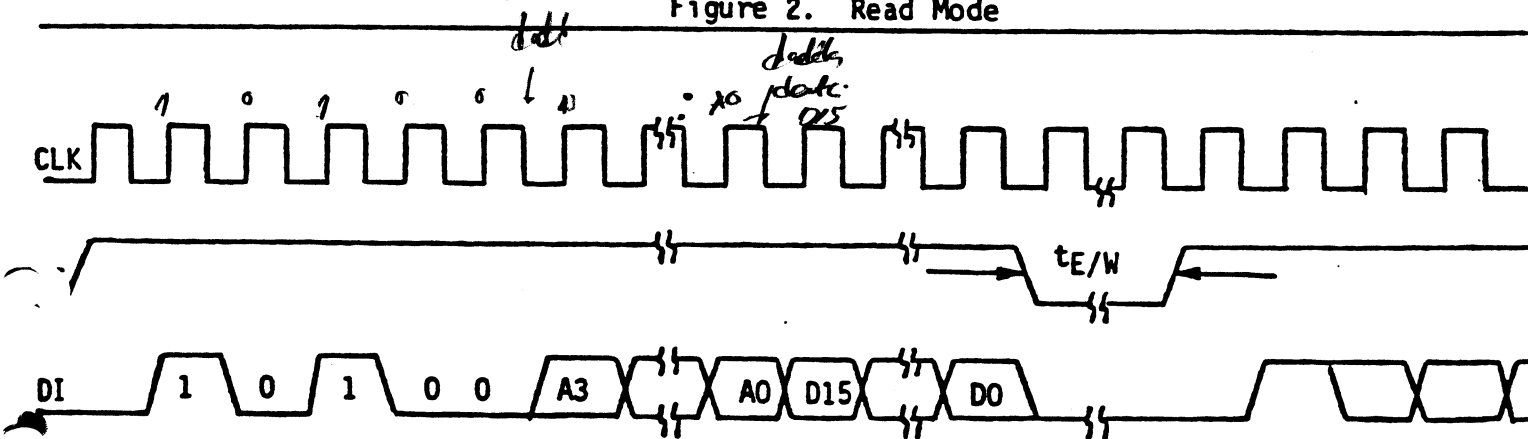


Data lags of vid



The READ instruction is the only instruction which outputs serial data on the DO pin. Only during the READ mode is the output pin (DO) valid. During all other modes the DO pin is in tri-state, eliminating bus contention. After a READ instruction is received, the instruction and address are decoded, followed by data transfer from the memory register into a 16-bit serial-out shift register. A dummy bit (logical "0") precedes the 16-bit data output string. The output data changes during the high state of the system clock.

Figure 2. Read Mode



The WRITE instruction is followed by 16 bits of data which are written into the specified address. This register must have been previously erased. Like any programming mode, erase/write time is determined by the low state of CS following the instruction. The on-chip high voltage section only generates high voltage during these programming modes which prevents spurious programming during other modes. When CS rises to V_{IH} , the programming cycle ends. All programming modes should be ended with CS high for one clock period, or followed by another instruction.

Figure 3. Write Mode